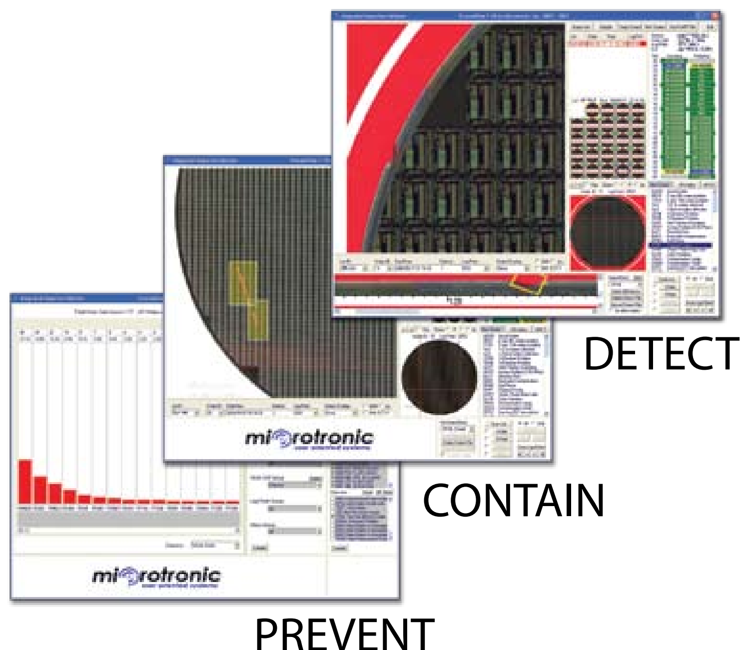
microtronic
user oriented systems

EAGLEview

Macro Defect Management

Zero Defect Strategy



"Prevent shipping defective die or test escapes"

PROCESSview *Off-line Analysis*

Complements EAGLEview for remote real-time process monitoring. Statistical data mining and Pareto for immediate root cause analysis is included. Image review provides wafer lot history and full wafer image retrieval for up to two years in seconds.

- ***High speed full wafer analysis***
- ***No device dependent recipes needed***
- ***Proprietary edge chip detection***
- ***OCR based wafer tracking***
- ***Randomize wafers to target defect source***
- ***Guard band (Ink-off) defective wafer areas***
- ***Ideal for Photo, CMP, Etch...***

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